

# ICI E450 L-EFT

Pulse E-Field Source

**LANGER**  
EMV-Technik



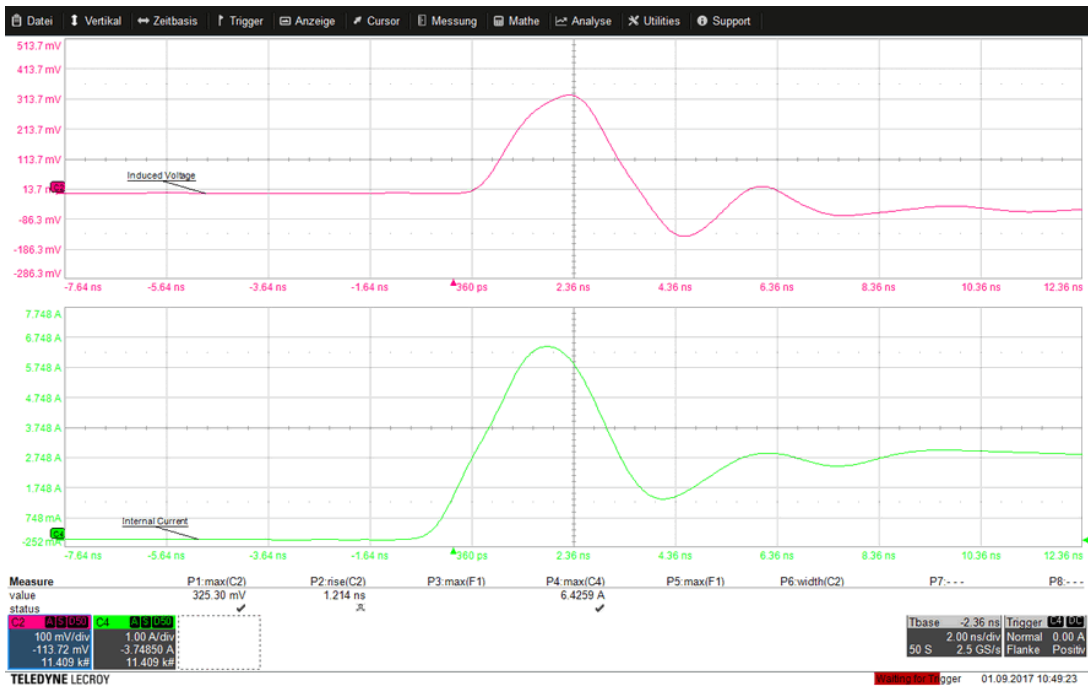
## Short description

The ICI E450 L-EFT pulse electric field source couples fast transient pulses into a test IC (open die). This allows for side channel analysis or testing the immunity of individual areas of the IC.

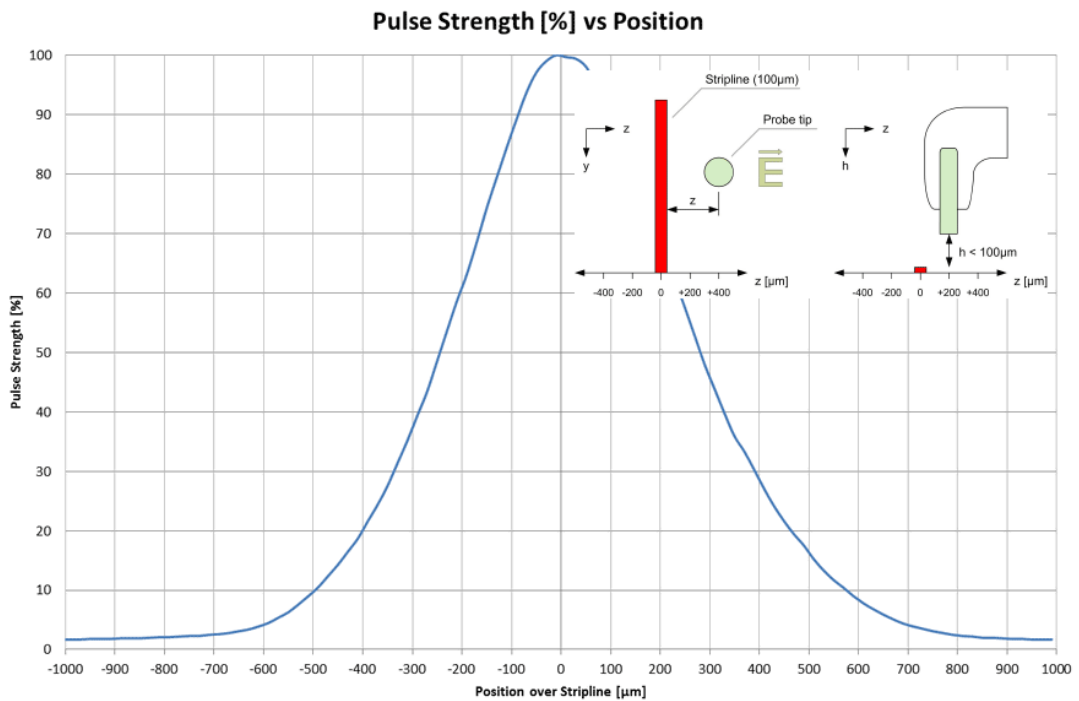
## Technical parameters

探头尺寸	Ø 450 µm
Max. Displacement Current (Stripline 100 µm)	7 mA
脉冲参数	
上升时间	< 2 ns
重复频率	0.1 Hz - 20 kHz
极性 (set by software)	+ / - / alternating
测量输出	50 Ω
触发器脉冲延迟 (Bypass Modus - Delay Line)	
min. 触发器脉冲延迟 (typ.)	70 ns
max. 触发器脉冲延迟 (typ.)	420 ns
max. Jitter (typ.)	± 1 ns
电源电压	BPS 202
重量	70 g
尺寸 (L x W x H)	(26 x 43 x 53) mm

脉冲形状



横向扫描



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Application of ICI E450 L-EFT pulse E-field source

